



<p style="text-align: center;">Searched</p> 	<p>Application/Control No.</p> <p>10671777</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>PECK ET AL.</p>
	<p>Examiner</p> <p>Kaplan, Hal I</p>	<p>Art Unit</p> <p>2836</p>

Class	SubClass	Date	Examiner
219	485	09/13/2006	HK
361	65	09/13/2006	HK

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Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10671777	PECK ET AL.
	Examiner Kaplan, Hal I	Art Unit 2836

Notes	Date	Examiner
219/483,485,486,508 (consulted Mark Paschall)	02/16/2006	HK
361/62,63,65 (consulted Stephen W. Jackson)	02/16/2006	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TD B) - See Search History Printout	09/13/2006	HK
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